



IIT Bombay Nanofabrication Facility

Tool Name: Dektak Profilometer 1.1 lab

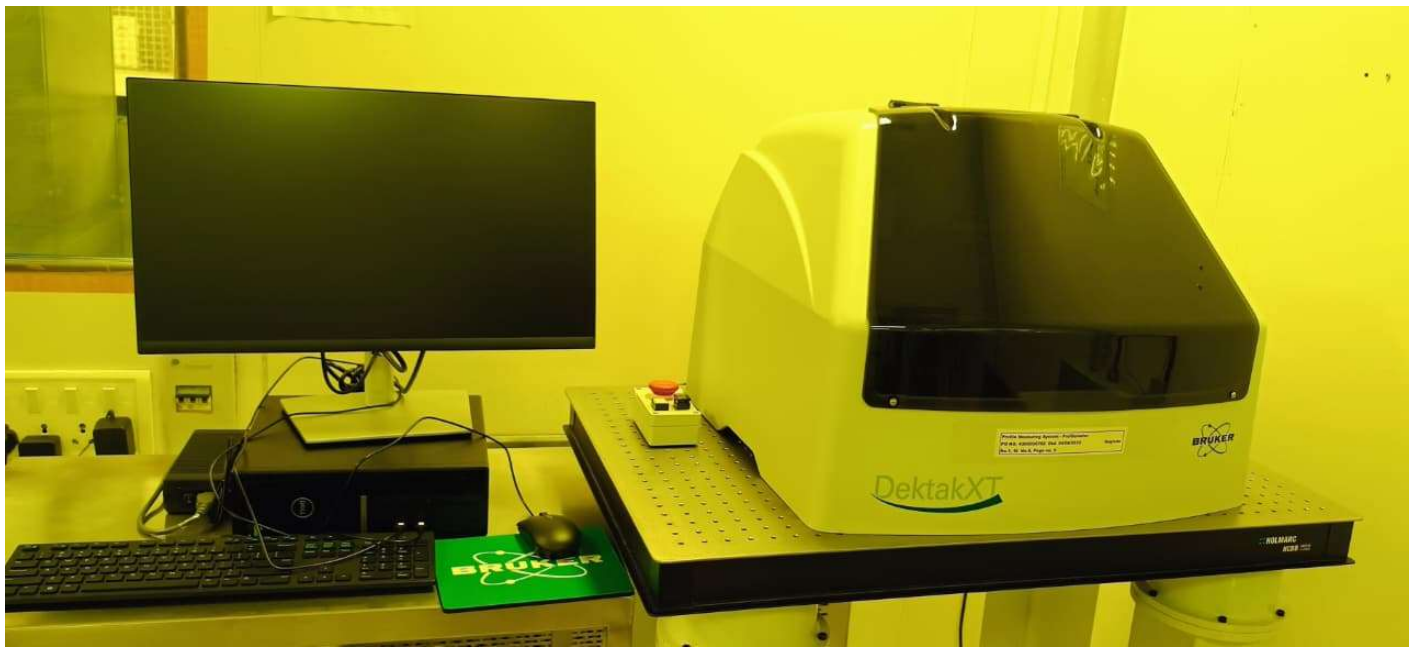
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Front View



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SPECIFICATIONS

- Equipment compatible with 2", 4", 6" and 8" wafers
- Stylus, LIS 3, 2um Radius - Type B
- Scan length - upto 30 mm
- Vertical resolution - less than or equal to 1 A° for 2 um vertical step
- Step height repeatability: 6A° or lower for a 1 um step
- Stylus size: 0.2 um , 2 um and 12.5 um
- Capable of measuring samples: up to 50 mm thick
- Field of view: 1 mm to 4 mm
- Profile auto-leveling and stitching software
- Stylus force : 1mg-15mg